

WO 03/035797

PCT/US02/33280

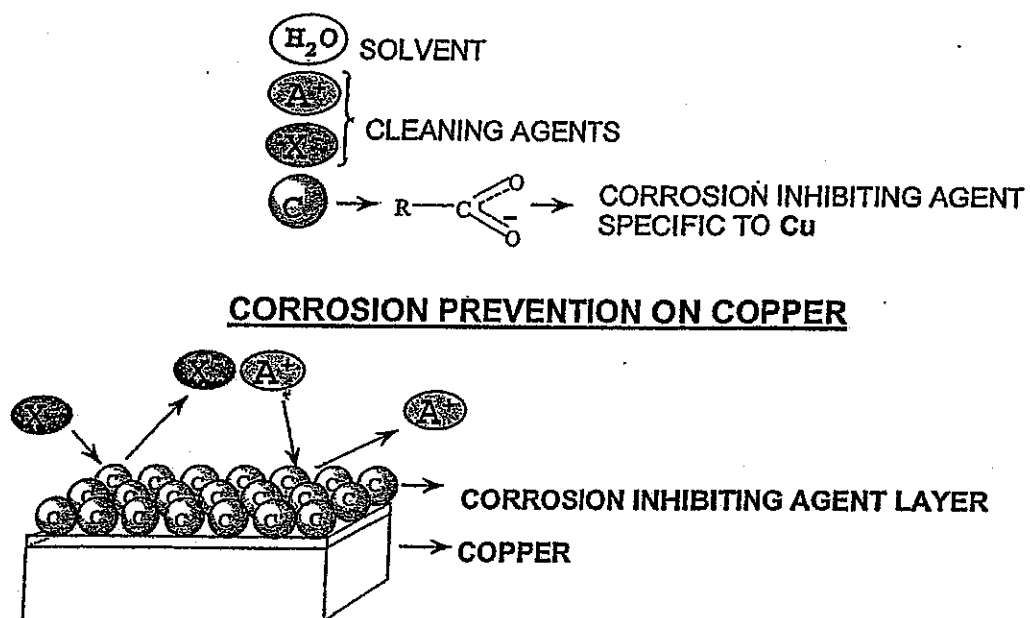
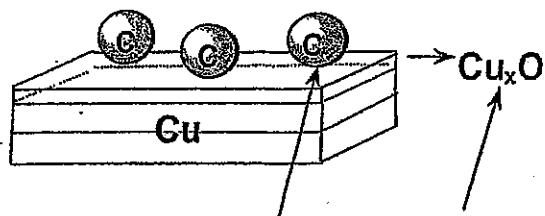


FIGURE 1

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CONTAMINATION TEST*

SAMPLE**	Cu (atoms/cm ²)	F (atoms/cm ²)	C (atoms/cm ²)	Cu _x O (Å)
CONTROL	1.6×10^{10}	3.3×10^{13}	7.5×10^{13}	42
Matrix 2 + IMINODIACETIC ACID INHIBITOR	8.5×10^9	5.1×10^{13}	1.5×10^{13}	15

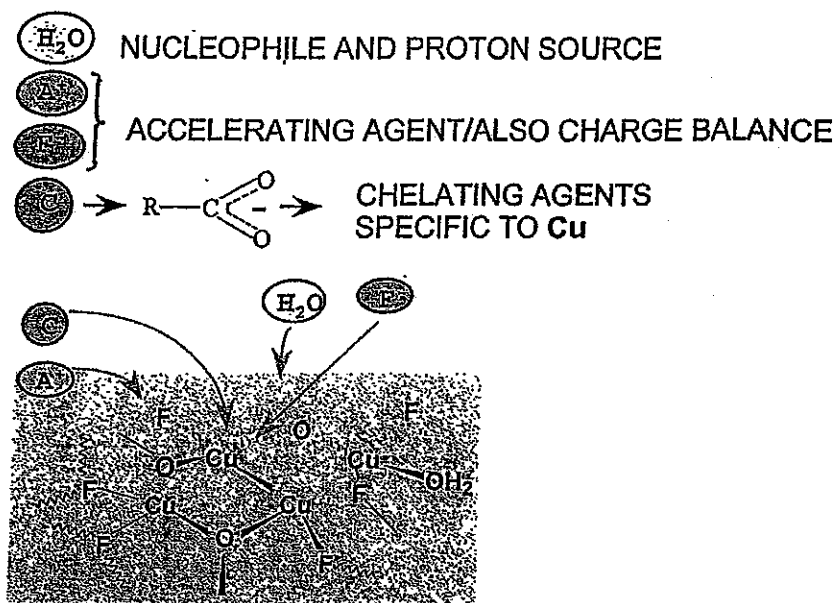
* Blanket Cu and Si Films Processed Together,
20 mL of Chemical (25 °C @ 15 min, DI Water Rinse)

** Average of 3 Points

FIGURE 2

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INSOLUBLE INORGANIC SLURRY AND RESIDUES

FIGURE 3

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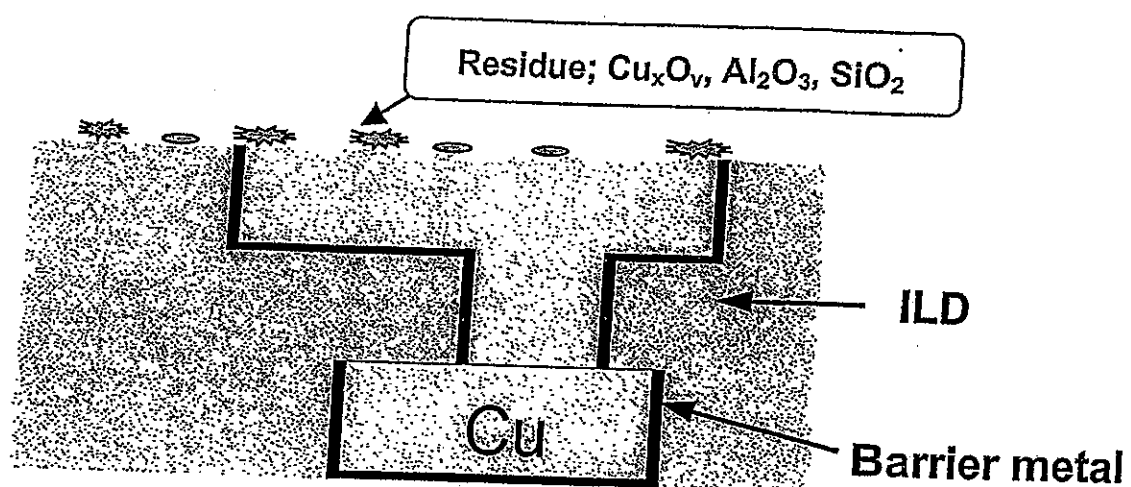


FIGURE 4

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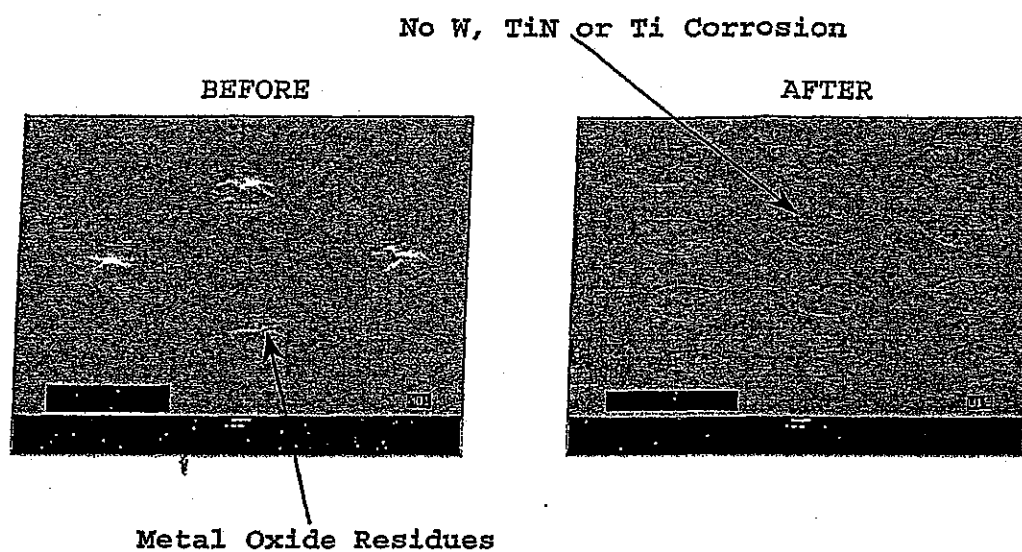


FIGURE 5

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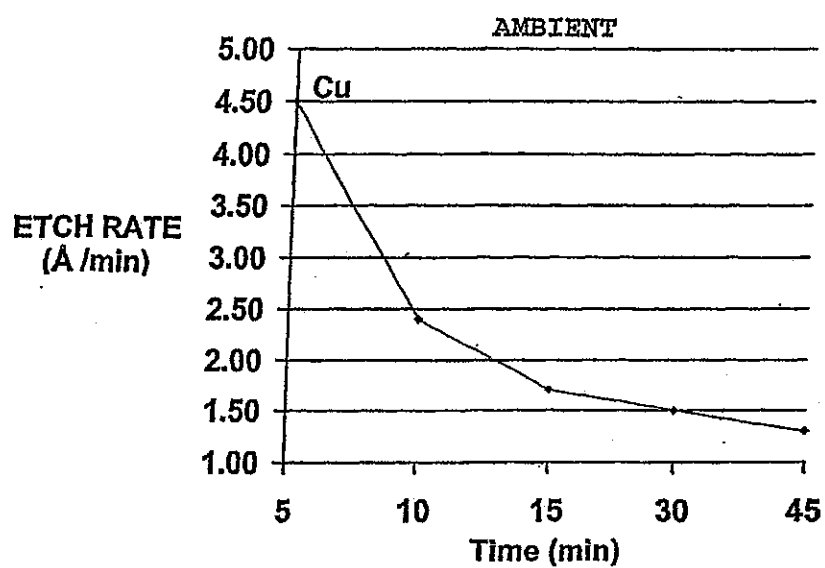


FIGURE 6